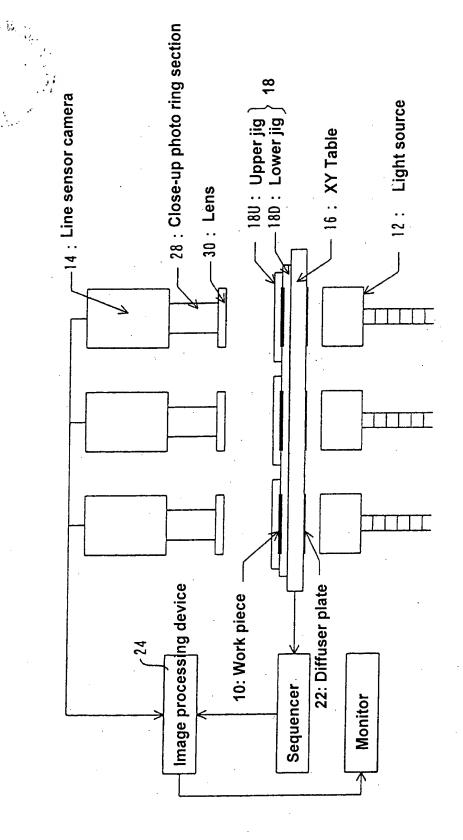
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Title: METHOD FOR EXAMINING FOREIGN MATTERS IN THROUGH HOLES In THROUGH HOLES Any. Ref. No.: 9319S-000197

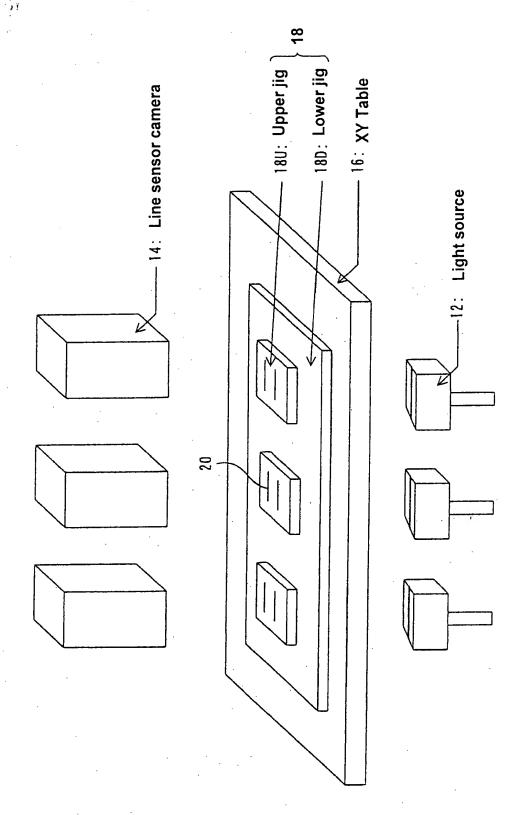
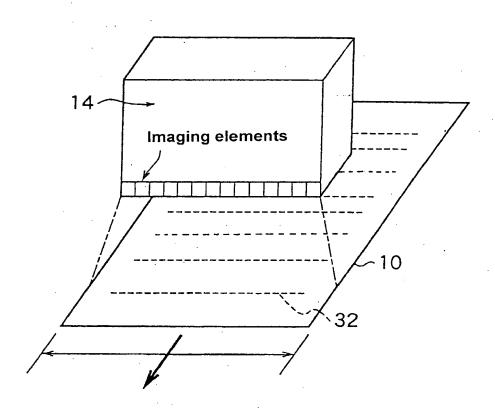


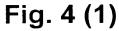


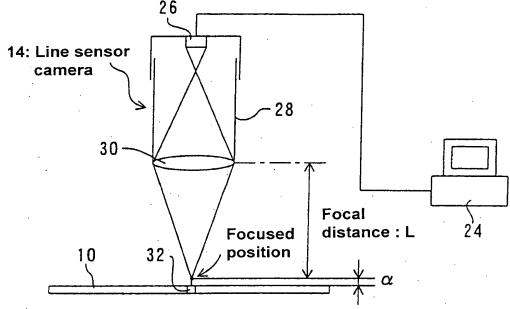
Fig. 3



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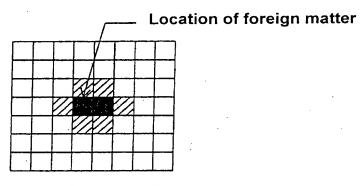
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Out-of-focus state (work piece surface + α)

Fig. 4 (2)



Out-of-focus condition

(Size of foreign matter: 8 pixels)

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Fig. 5 (1)

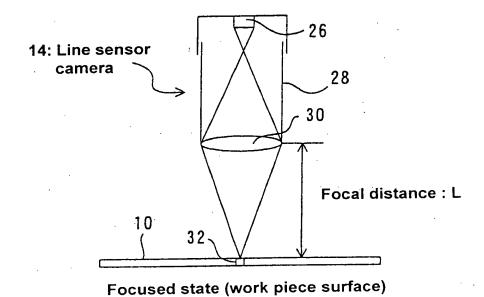
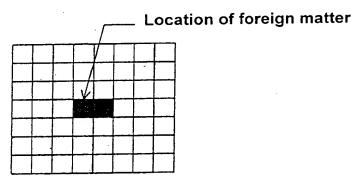


Fig. 5 (2)



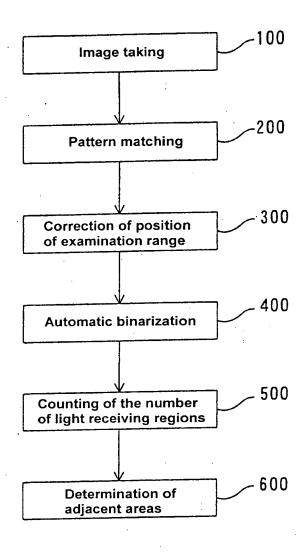
Focused condition

(Size of foreign matter : 2 pixels)

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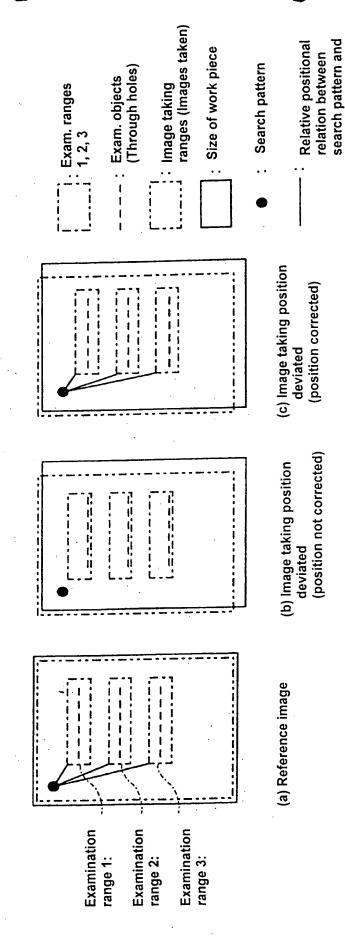
Fig. 6



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examination ranges

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Fig. 8 (1)

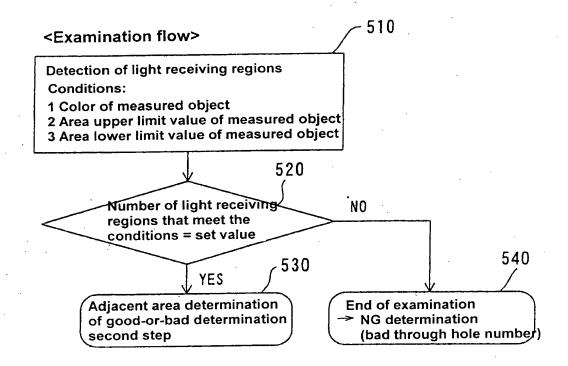
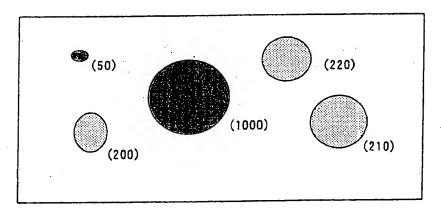


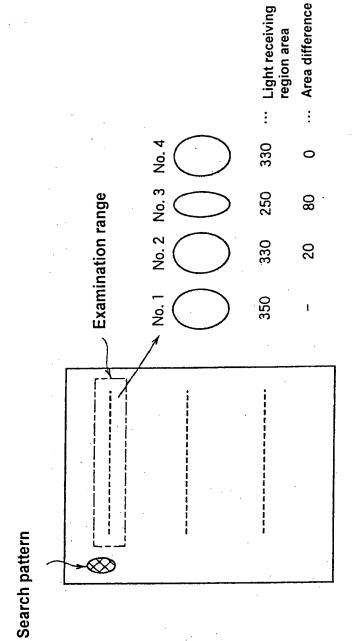
Fig. 8 (2)

<Description of area upper limit values and area lower limit values of measured objects>



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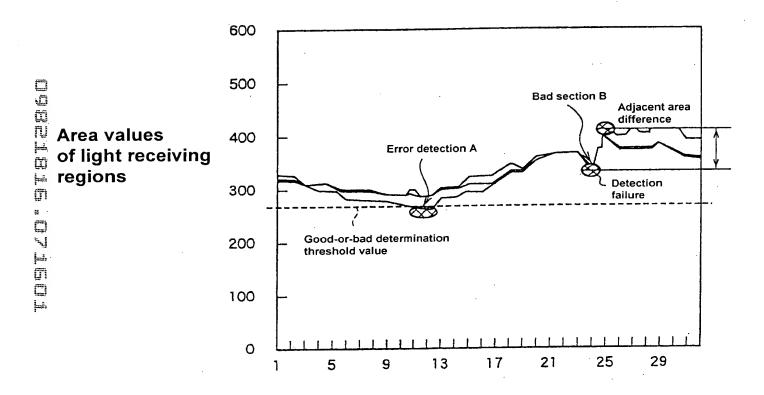
Fig. 9



ex) Bad if area difference is 50 or over

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Fig. 10



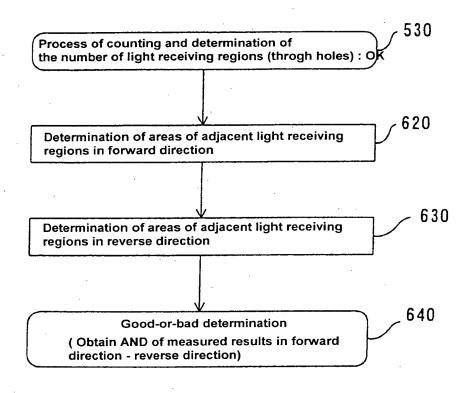
Position of through holes

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Fig. 11

<< Flow of adjacent area determination>>

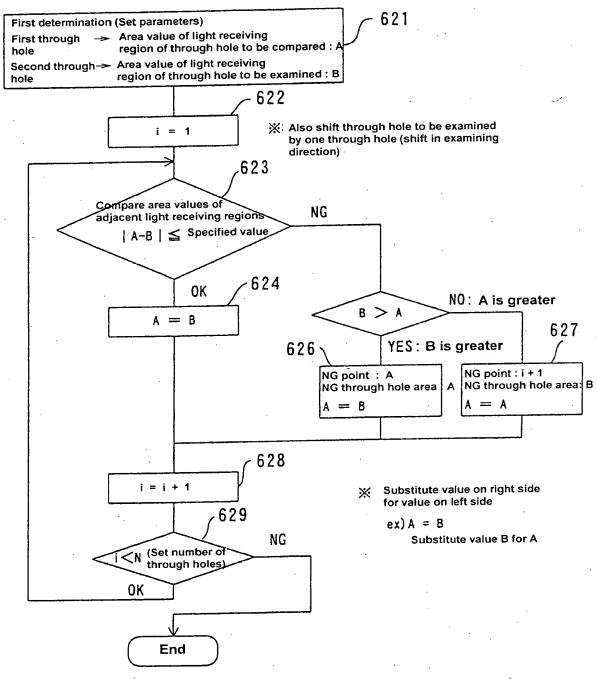


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Fig. 12

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<< Flow of adjacent area determination process and Examination of each examination range>>



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Fig. 13 (1)

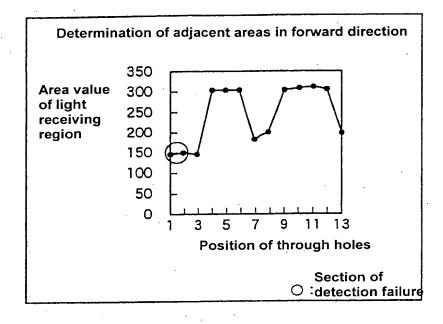
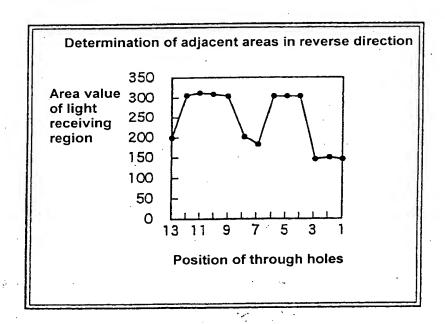


Fig. 13 (2)



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Fig. 14

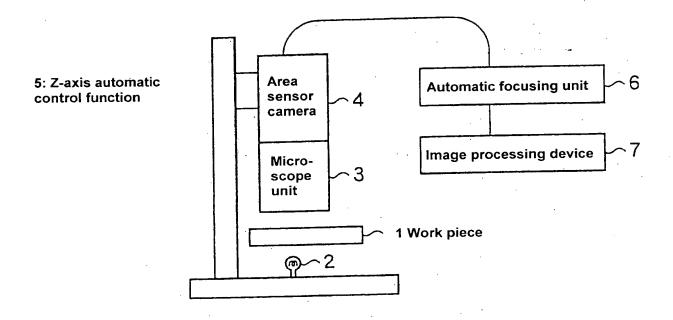
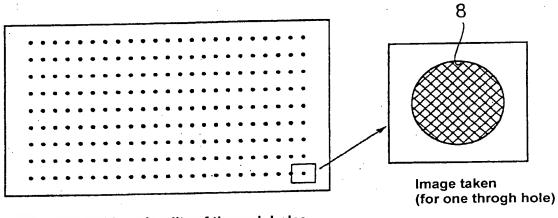


Fig. 15

CYBRISTS CYISOI



Work piece with a plurality of through holes